

NanoMetrology Seminar

Beam Line User Seminar Dual Polarisation Interferometry

Dual Polarisation Interferometry (DPI) is an analytical technique used to understand the structure and function of a wide range of molecular systems through quantitative measurement.

DPI provides real-time, high-resolution measurements of molecular size, density and mass. DPI data can be compared directly with complementary techniques such as NMR, x-ray crystallography, SPR, QCM and neutron reflection.

The seminar is aimed at beam-line users who might wish to consider DPI as a supplementary investigative technique.

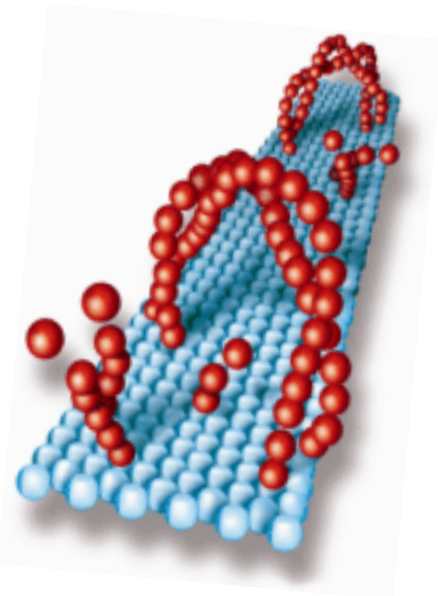
Presentations on the use and applications of DPI will be given by representatives of:

University of Liverpool - the first purchaser of a commercial DPI instrument

University of Manchester - a beam-user perspective on DPI

Farfield Scientific - the North West innovator behind DPI and its commercial iteration, the *AnaLight*[®]

With grateful thanks to the NWDA for helping us to organise this event



Join us on

Monday 4th June 2007

8.30am (breakfast served) to 11.00am

In the Presentation Suite at the Daresbury Innovation Centre

To book your place please use the 'fax back' form overleaf, or contact Maggi Blakebrough at Farfield Scientific

Tel: 0870 950 9717

E-mail: mblakebrough@farfield-scientific.com

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The seminar will take place in the Presentation Suite,
Daresbury Innovation Centre, Keckwick Lane,
Daresbury, Cheshire, WA4 4FS

**Full agenda and travel details will be sent upon
registration**

FAX BACK FORM

**Please register me for the NanoMetrology
Seminar on
Monday 4th June 2007**

Name

Institute/Company.....

Address

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Telephone.....

E-mail:

FAX TO 0870 950 9718